

TMUX9612 220V, Flat Ron, 1:1 (SPST), 4-Channel Switches with Latch-Up Immunity and 1.8V Logic

1 Features

· High supply voltage capable:

Dual supply: ±10V to ±110V

- Single supply: 10V to 140V

 Asymmetric dual supply operation: between +90V / –130V and 140V / -80V

Consistent parametric across supply voltages

Latch-up immune

High continuous current: 200mA
Low input leakage: 80pA at 25°C

· Low charge injection: -20pC

Low off isolation & crosstalk: < –100dB
 Low On-Resistance flatness: 0.435Ω

Low On-Resistance: 14Ω
Low off-capacitance: 5pF

Removes need for additional logic rail (V_I)

1.8-V Logic capable

· Fail-safe logic: up to 48 V independent of supply

Integrated Pull-Down resistor on logic pins

Bidirectional signal path

Wide operating temperature T_A: –40°C to 125°C

Industry-standard, small WQFN package

2 Applications

- High voltage bidirectional switching
- · Analog and digital signal switching
- Semiconductor test equipment
- LCD test equipment
- · Battery test equipment
- Data acquisition systems (DAQ)
- Digital multi-meter (DMM)
- · Factory automation and control
- Programmable logic controllers (PLC)
- · Analog input modules

3 Description

The TMUX9612 is a modern high voltage capable analog switch with Latch-Up immunity. Each device has four independently controllable 1:1, single-pole single-throw (SPST) switch channels. The device works well with dual supplies, a single supply, or asymmetric supplies up to a maximum supply voltage of 220V. The TMUX9612 device provides consistent analog parametric performance across the entire supply voltage range. The device also supports bidirectional analog and digital signals on the source (Sx) and drain (Dx) pins.

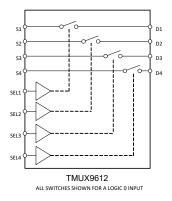
All logic inputs support logic levels of 1.8V, 3.3V, and 5V and can be connected as high as 48V, allowing for system flexibility with control signal voltage. Fail-safe logic circuitry allows voltages on the logic pins to be applied before the supply pin, protecting the device from potential damage.

The device provides Latch-Up immunity, preventing undesirable high current events between parasitic structures within the device. A Latch-Up condition typically continues until the power supply rails are turned off and can lead to device failure. The Latch-Up immunity feature allows this family of multiplexers to be used in harsh environments.

Package Information

PART NUMBER ⁽²⁾	PACKAGE ⁽¹⁾	BODY SIZE (NOM)		
TMUX9612	RUM (WQFN, 16)	4.00mm × 4.00mm		

- For all available packages, see the orderable addendum at the end of the data sheet.
- (2) See the Device Comparison Table.



Functional Block Diagram



Table of Contents

1 Features1	7.6 Off Isolat
2 Applications 1	7.7 Crosstalk
3 Description1	7.8 Bandwidt
4 Device Comparison Table3	7.9 THD + N
5 Pin Configuration and Functions4	8 Detailed Des
6 Specifications5	8.1 Overview
6.1 Absolute Maximum Ratings: TMUX961x Devices 5	8.2 Functions
6.2 ESD Ratings5	8.3 Feature D
6.3 Recommended Operating Conditions:	8.4 Device F
TMUX961x Devices5	9 Application a
6.4 Source and Drain Continuous Current6	9.1 Application
6.5 Source and Drain Pulse Current6	9.2 Typical A
6.6 Electrical Characteristics (Global): TMUX961x	9.3 Power Sเ
Devices6	9.4 Layout
6.7 Electrical Characteristics (±110V Dual Supply)7	10 Device and
6.8 Electrical Characteristics (±50V Dual Supply)8	10.1 Docume
6.9 Electrical Characteristics (100V Single Supply)9	10.2 Receivii
6.10 Switching Characteristics: TMUX961x Devices10	10.3 Support
6.11 Typical Characteristics11	10.4 Tradem
7 Parameter Measurement Information	10.5 Electros
7.1 On-Resistance	10.6 Glossar
7.2 Off-Leakage Current13	11 Revision Hi
7.3 On-Leakage Current14	12 Mechanical
7.4 Device Turn-On and Turn-Off Time14	Information.
7.5 Charge Injection15	

7.6 Off Isolation1	5
7.7 Crosstalk1	6
7.8 Bandwidth1	6
7.9 THD + Noise1	7
8 Detailed Description1	8
8.1 Overview1	8
8.2 Functional Block Diagram1	8
8.3 Feature Description1	
8.4 Device Functional Modes2	20
9 Application and Implementation2	12
9.1 Application Information	
9.2 Typical Application2	12
9.3 Power Supply Recommendations2	23
9.4 Layout2	23
10 Device and Documentation Support2	25
10.1 Documentation Support2	25
10.2 Receiving Notification of Documentation Updates2	25
10.3 Support Resources2	25
10.4 Trademarks2	25
10.5 Electrostatic Discharge Caution2	25
10.6 Glossary2	25
11 Revision History2	25
12 Mechanical, Packaging, and Orderable	
Information2	25



4 Device Comparison Table

PRODUCT	DESCRIPTION
TMUX9612	High Voltage, 4-channel, 1:1 (SPST) switches, (Logic High)



5 Pin Configuration and Functions

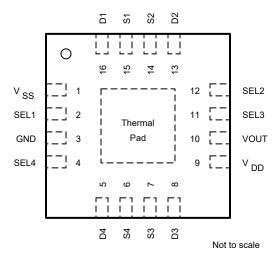


Figure 5-1. RUM Package, 16-Pin WQFN (Top View)

Table 5-1. Pin Functions

P	IN	TYPE ⁽¹⁾	DESCRIPTION
NAME	WQFN	ITPE\''	DESCRIPTION
D1	16	I/O	Drain pin 1. Can be an input or output.
D2	13	I/O	Drain pin 2. Can be an input or output.
D3	8	I/O	Drain pin 3. Can be an input or output.
D4	5	I/O	Drain pin 4. Can be an input or output.
GND	3	Р	Ground (0 V) reference
S1	S1 15 I/O Source pin 1. Can be an input or output.		Source pin 1. Can be an input or output.
S2	S2 14 I/O Source pin 2. Can be an input or output.		Source pin 2. Can be an input or output.
S3	7	I/O	Source pin 3. Can be an input or output.
S4	6	I/O	Source pin 4. Can be an input or output.
SEL1	2	I	Logic control input 1.
SEL2	12	I	Logic control input 2.
SEL3	11	I	Logic control input 3.
SEL4	4	I	Logic control input 4.
VOUT	10	Р	Internally generated voltage output rail. For reliable operation, connect a decoupling capacitor ranging from 0.01µF to 0.1µF between VOUT and GND on pin 10 or on the thermal pad. Having the decoupling capacitor as close to the thermal pad as possible yeilds the best performance.
V _{DD}	9	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from $1\mu F$ to $10\mu F$ between V_{DD} and GND.
V _{SS} 1 P th		Р	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 1µF to 10µF between V _{SS} and GND.
Thermal Pa	d (VOUT)	Р	The thermal pad is internally connected to VOUT (same node as pin 10). VOUT is an internally generated voltage output rail. For reliable operation, connect a decoupling capacitor ranging from $0.01\mu\text{F}$ between VOUT and GND on pin 10 or on the thermal pad. Having the decoupling capacitor as close to the thermal pad as possible yeilds the best performance.

(1) I = input, O = output, I/O = input and output, P = power



6 Specifications

6.1 Absolute Maximum Ratings: TMUX961x Devices

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V _{DD} -V _{SS}			240	V
V_{DD}	Supply voltage	-0.5	240	V
V _{SS}		-135	0.5	V
V _{SELx}	Logic control input pin voltage (SELx)	-0.5	50	V
I _{SELx}	Logic control input pin current (SELx)	-30	30	mA
V _S or V _D	Source or drain voltage (Sx, Dx)	V _{SS} -2	V _{DD} +2	V
I _{DC}	Source or drain continuous current (Sx, Dx)	-200	200	mA
I _{IK} (2)	Diode clamp current at 85°C	-100	100	mA
'IK ' '	Diode clamp current at 125°C	-15	15	mA
T _{stg}	Storage temperature	-65	150	°C
T _A	Ambient temperature	-55	150	°C
TJ	Junction temperature		150	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	V
V _(ESD)		Charged device model (CDM), per ANSI/ESDA/JEDEC JS-002, all pins ⁽²⁾	±500	V

⁽¹⁾ JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions: TMUX961x Devices

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{DD} - V_{SS}$	Power supply voltage differential	10	220	V
V _{DD}	Positive power supply voltage	10	140	V
V _{SS}	Negative power supply voltage	-130	0	V
V _S or V _D	Signal path input/output voltage (source or drain pin)	V _{SS}	V _{DD} ⁽¹⁾	V
V _{SEL}	Logic input pin voltage	0	48	V
T _A	Ambient temperature	-40	125	°C
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)		I _{DC} ⁽²⁾	mA

R_{ON} and R_{ON_FLAT} will increase when operating V_S or V_D greater than V_{DD} - 5V. Other Electrical Characterisitics specifications may be violated as well.

(2) Refer to Source or Drain Continuous Current table for IDC specifications.

⁽²⁾ Signal path pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.

⁽²⁾ JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.



6.4 Source and Drain Continuous Current

over operating free-air temperature range (unless otherwise noted)

	PACKAGE			MIN	NOM	MAX	UNIT
		Continuous current through switch for 1 channel	T _A = 25°C			200	
I _{DC} 1 ch ⁽¹⁾	RUM (WQFN)		T _A = 85°C			200	mA
			T _A = 125°C			110	
	I RI IIVI (VV() EIVI)	WQFN) Continuous current through switch on all channels at the same time	T _A = 25°C			150	
I _{DC} All ch ⁽²⁾			T _A = 85°C			100	mA
			T _A = 125°C			55	

⁽¹⁾ Max continuous current shown for a single channel at a time.

6.5 Source and Drain Pulse Current

over operating free-air temperature range (unless otherwise noted)

	PACKAGE			MIN	NOM	MAX	UNIT
		Pulse ⁽²⁾ current through switch on all channels at the same time	T _A = 25°C			250	
I _{DC} All ch ⁽¹⁾			T _A = 85°C			200	mA
			T _A = 125°C			150	

¹⁾ Max pulse current shown for all channels at a time. Refer to max power dissipation (Ptot) to ensure package limitations are not violated.

6.6 Electrical Characteristics (Global): TMUX961x Devices

over operating free-air temperature range (unless otherwise noted) typical at V_{DD} = +110V, V_{SS} = -110V, GND = 0V and T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
LOGIC I	NPUTS					,	
V _{IH}	Logic voltage high		-40°C to +125°C	1.3		48	V
V _{IL}	Logic voltage low		-40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current	Logic inputs = 0V, 5V, or 48V	-40°C to +125°C		0.4	3.8	μA
I _{IL}	Input leakage current	Logic inputs = 0V, 5V, or 48V	-40°C to +125°C	-0.2	-0.005		μA
C _{IN}	Logic input capacitance		-40°C to +125°C		3		pF
POWER	SUPPLY					'	
			25°C		130	175	μΑ
I _{DD}	V _{DD} supply current	Logic inputs = 0V, 5V, or 48V	–40°C to +85°C			190	μA
			–40°C to +125°C			210	μΑ
			25°C		100	135	μA
I _{SS}	V _{SS} supply current	Logic inputs = 0V, 5V, or 48V	–40°C to +85°C			150	μA
			-40°C to +125°C			160	μA

⁽²⁾ Max continuous current shown for all channels at a time. Refer to max power dissipation (P_{tot}) to ensure package limitations are not violated.

⁽²⁾ Pulsed at 10ms, 10% duty cycle



6.7 Electrical Characteristics (±110V Dual Supply)

 V_{DD} = +110V, V_{SS} = -110V, GND = 0V (unless otherwise noted) Typical at T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
			25°C		14	19.6	
B	On-resistance	$V_S = -105V$ to +105V	-40°C to +50°C			21	
KON	On-resistance	$I_D = -10 \text{mA}$	-40°C to +85°C			22.4	Ω
ΔR _{ON} O ch			-40°C to +125°C			28	
			25°C		0.28	0.84	
A D	On-resistance mismatch between channels	$V_S = -105V$ to +105V	-40°C to +50°C			1	0
R _{ON FLAT} O		$I_D = -10 \text{mA}$	-40°C to +85°C			1.12	Ω
			-40°C to +125°C			1.4	
R _{ON FLAT}	On-resistance flatness	$V_S = -105V \text{ to } +105V$ $I_D = -10\text{mA}$	25°C		0.435		Ω
R _{ON DRIFT}	On-resistance drift	$V_S = 0V, I_S = -10mA$	-40°C to +125°C		0.08		Ω/°C
		V_{DD} = 110V, V_{SS} = -110V Switch state is off V_{S} = +105V / -105V V_{D} = -105V / +105V	25°C		80	TBD	pA
	Source off leakage current ⁽¹⁾		-40°C to +50°C	TBD	315	TBD	
'S(OFF)	Source on leakage current		-40°C to +85°C	TBD		TBD	
			-40°C to +125°C	TBD		TBD	
		V _{DD} = 110V, V _{SS} = -110V	25°C		80	TBD	1
	Drain off leakage current ⁽¹⁾	Switch state is off	-40°C to +50°C	TBD	315	TBD	
D(OFF)	Diam on leakage current	$V_S = +105V / -105V$	-40°C to +85°C	TBD		TBD	рA
		$V_D = -105V / +105V$	-40°C to +125°C	TBD		TBD	
			25°C		-50	TBD	
I _{S(ON)}	Channel on leakage current ⁽²⁾	V _{DD} = 110V, V _{SS} = -110V Switch state is on	-40°C to +50°C	TBD	120	TBD	- Aq
	Chamile on leakage current	$V_S = V_D = \pm 105V$	-40°C to +85°C	TBD		TBD	
			-40°C to +125°C	TBD		TBD	

⁽¹⁾ (2) When V_S is positive, V_D is negative. And when V_S is negative, V_D is positive. When V_S is at a voltage potential, V_D is floating. And when V_D is at a voltage potential, V_S is floating.



6.8 Electrical Characteristics (±50V Dual Supply)

 V_{DD} = +50V, V_{SS} = -50V, GND = 0V (unless otherwise noted) Typical at T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS T _A		MIN	TYP	MAX	UNIT		
ANALOG	SWITCH			'					
	On-resistance		25°C		14	19.6			
В		V _S = –45V to 45V	-40°C to +50°C			21	Ω		
R _{ON}		$I_D = -10 \text{mA}$	-40°C to +85°C			22.4			
			-40°C to +125°C			28	Ì		
			25°C		0.28	0.84			
۸۵	On-resistance mismatch between	V _S = –45V to 45V	-40°C to +50°C			1	Ω		
ΔR _{ON}	channels	$I_D = -10 \text{mA}$	-40°C to +85°C			1.12			
			-40°C to +125°C			1.4			
R _{ON FLAT}	On-resistance flatness	$V_S = -45V \text{ to } 45V$ $I_D = -10\text{mA}$	25°C		0.4		Ω		
R _{ON DRIFT}	On-resistance drift	$V_S = 0V, I_S = -10mA$	-40°C to +125°C		0.08		Ω/°C		
	Source off leakage current ⁽¹⁾	V = 50\/ \/ = 50\/	25°C		30	TBD			
		V_{DD} = 50V, V_{SS} = -50V Switch state is off	-40°C to +50°C	TBD	130	TBD	pА		
I _{S(OFF)}		$V_S = +45V / -45V$	-40°C to +85°C	TBD		TBD			
		V _D = -45V / +45V	-40°C to +125°C	TBD		TBD			
	Drain off leakage current ⁽¹⁾	V _{DD} = 50V, V _{SS} = -50V	25°C		30	TBD			
		Switch state is off	-40°C to +50°C	TBD	130	TBD			
I _{D(OFF)}		$V_S = +45V / -45V$	-40°C to +85°C	TBD		TBD	рA		
		V _D = -45V / +45V	-40°C to +125°C	TBD		TBD			
I _{S(ON)}	Channel on leakage current ⁽²⁾		25°C		-35	TBD			
		V_{DD} = 50V, V_{SS} = -50V Switch state is on	-40°C to +50°C	TBD	25	TBD	nΛ		
I _{D(ON)}		$V_S = V_D = \pm 45V$	-40°C to +85°C	TBD		TBD	рA		
		_	-40°C to +125°C	TBD		TBD			

- When V_{S} is positive, V_{D} is negative. And when V_{S} is negative, V_{D} is positive.
- (1) (2) When V_S is at a voltage potential, V_D is floating. Or when V_D is at a voltage potential, V_S is floating.



6.9 Electrical Characteristics (100V Single Supply)

 V_{DD} = +100V, V_{SS} = 0V, GND = 0V (unless otherwise noted) Typical at T_A = 25°C (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT	
SWITCH							
		25°C		14	19.6		
On-resistance	V _S = 0V to +95V	-40°C to +50°C			21	Ω	
	$I_D = -10 \text{mA}$	-40°C to +85°C			22.4		
		-40°C to +125°C			28		
		25°C		0.28	0.84		
On-resistance mismatch between	V _S = 0V to +95V	-40°C to +50°C			1	Ω	
channels	$I_D = -10 \text{mA}$	-40°C to +85°C			1.12		
		-40°C to +125°C			1.4		
On-resistance flatness	$V_S = 0V \text{ to } +95V$ $I_D = -10\text{mA}$	25°C		0.36		Ω	
On-resistance drift	V _S = 50V, I _S = -10mA	-40°C to +125°C		0.08		Ω/°C	
Source off leakage current ⁽¹⁾	\/ - 100\/ \/ - 0\/	25°C		30	TBD		
	Switch state is off	-40°C to +50°C	TBD	130	TBD		
	$V_S = +95V / 0V$	-40°C to +85°C	TBD		TBD	рA	
	V _D = 0V / +95V	-40°C to +125°C	TBD		TBD		
Drain off leakage current ⁽¹⁾	\/ - 100\/ \/ - 0\/	25°C		30	TBD	.	
	Switch state is off	-40°C to +50°C	TBD	130	TBD		
	$V_S = +95V / 0V$	-40°C to +85°C	TBD		TBD	рA	
	V _D = 0V / +95V	-40°C to +125°C	TBD		TBD		
Channel on leakage current ⁽²⁾		25°C		-35	TBD		
	$V_{DD} = 100V$, $V_{SS} = 0V$	-40°C to +50°C	TBD	30	TBD	ο Λ	
	$V_S = V_D = 0V / +95V$	-40°C to +85°C	TBD		TBD	рA	
		-40°C to +125°C	TBD		TBD		
	On-resistance On-resistance mismatch between channels On-resistance flatness On-resistance drift Source off leakage current(1) Drain off leakage current(1)	On-resistance $V_S = 0V \text{ to } +95V$ $I_D = -10\text{mA}$ On-resistance mismatch between channels $V_S = 0V \text{ to } +95V$ $I_D = -10\text{mA}$ On-resistance flatness $V_S = 0V \text{ to } +95V$ $I_D = -10\text{mA}$ On-resistance drift $V_S = 50V, I_S = -10\text{mA}$ On-resistance drift $V_S = 50V, I_S = -10\text{mA}$ Source off leakage current(1) $V_D = 100V, V_S = 0V$ Switch state is off $V_S = +95V / 0V$ $V_D = 0V / +95V$ Channel on leakage current(2) $V_D = 100V, V_S = 0V$ Switch state is on			$ \begin{tabular}{l l l l l l l l l l l l l l l l l l l $	$ \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	

⁽¹⁾ (2) When V_S is positive, V_D is negative. And when V_S is negative, V_D is positive. When V_S is at a voltage potential, V_D is floating. Or when V_D is at a voltage potential, V_S is floating.



6.10 Switching Characteristics: TMUX961x Devices

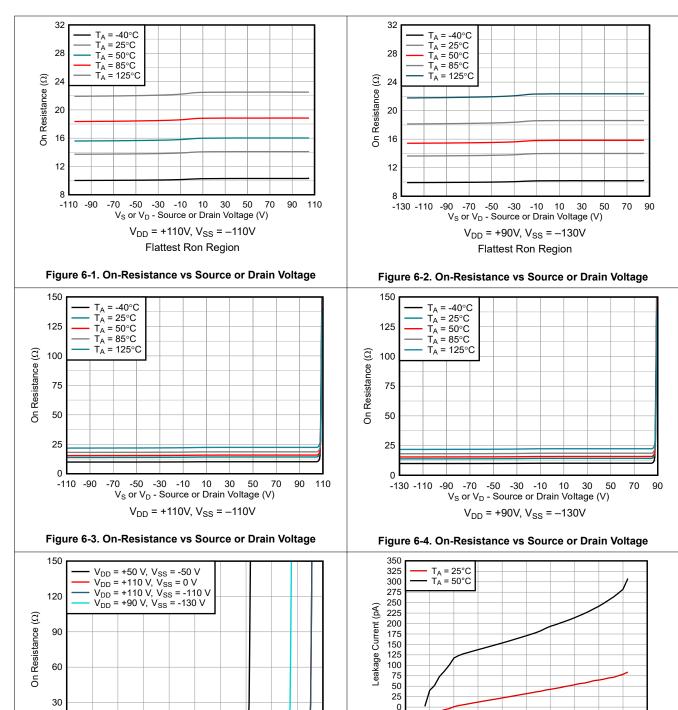
over operating free-air temperature range (unless otherwise noted) typical at V_{DD} = +110V, V_{SS} = -110V, GND = 0V and T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN TYP	MAX	UNIT
			25°C	40		
t _{ON (EN)}	Turn-on time from enable	$V_S = 10V$ $R_1 = 300\Omega, C_1 = 35pF$	-40°C to +85°C		75	μs
		π – 50052, ΟΕ – 50βι	-40°C to +125°C		75	
			25°C	18		
t _{OFF (EN)}	Turn-off time from enable	$V_S = 10V$ $R_1 = 300\Omega, C_1 = 35pF$	-40°C to +85°C		35	μs
		11t 00011, 0t 00p1	-40°C to +125°C		35	
t _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} ramp rate = 20V/ μ s, V_{S} = 10V R_{L} = 300 Ω , C_{L} = 35pF	25°C	45		μs
t _{PD}	Propagation delay	$R_L = 50\Omega$, $C_L = 5pF$	25°C	410		ps
Q _{INJ}	Charge injection	$V_S = (V_{DD} + V_{SS}) / 2$, $C_L = 1$ nF	25°C	-20		рС
O _{ISO}	Off isolation	$R_L = 50\Omega$, $C_L = 5pF$ $V_S = (V_{DD} + V_{SS}) / 2$, $f = 100kHz$	25°C	-104		dB
X _{TALK}	Inter-channel crosstalk	$R_L = 50\Omega$, $C_L = 5pF$ $V_S = (V_{DD} + V_{SS}) / 2$, $f = 100kHz$	25°C	-110		dB
BW	–3dB bandwidth	$R_L = 50\Omega$, $C_L = 5pF$ $V_S = (V_{DD} + V_{SS}) / 2$	25°C	530		MHz
IL	Insertion loss	$R_L = 50\Omega$, $C_L = 5pF$ $V_S = (V_{DD} + V_{SS}) / 2$, $f = 1MHz$	25°C	-1.13		dB
ACPSRR	AC power supply rejection ratio	$\begin{aligned} &V_{PP} = 0.62 \text{V on } V_{DD} \text{ and } V_{SS} \\ &R_S = 5 \Omega, 0.01 \mu\text{F decoupling cap} \\ &\text{on VOUT} \\ &C_L = 50 \text{pF} \\ &\text{f} = 1 \text{MHz} \end{aligned}$	25°C	-70		dB
THD+N	Total harmonic distortion + Noise	$V_{PP} = (V_{DD} - V_{SS})/2V (20V \text{ cap}),$ $V_{S} = (V_{DD} + V_{SS})/2$ $R_{L} = 1k\Omega$, $C_{L} = 5pF$, f = 20Hz to 20kHz	25°C	0.0015		%
C _{S(OFF)}	Source off capacitance	$V_S = (V_{DD} + V_{SS}) / 2V, f = 1MHz$	25°C	5		pF
C _{D(OFF)}	Drain off capacitance	$V_S = (V_{DD} + V_{SS}) / 2V, f = 1MHz$	25°C	5		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = (V _{DD} + V _{SS}) / 2V, f = 1MHz	25°C	15		pF



6.11 Typical Characteristics

at $T_A = 25$ °C, $V_{DD} = +110$ V, and $V_{SS} = -110$ V (unless otherwise noted)



-25 -50 -125 -100

-75 -50 -25 0 25 50

-80 -55

-30

-5 V_S or V_D - Source or Drain Voltage (V)

Figure 6-5. On-Resistance vs Source or Drain Voltage

20 45 V_S or V_D- Source or Drain Voltage (V)

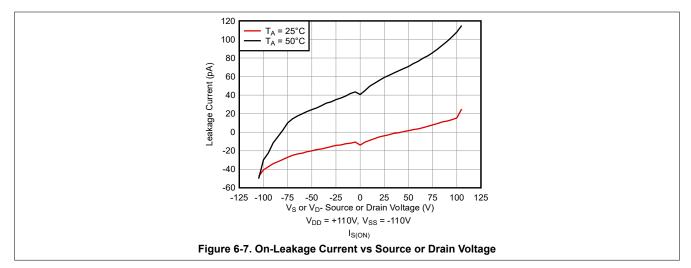
V_{DD} = +110V, V_{SS}= -110V $I_{S(OFF)}$ and $I_{D(OFF)}$

Figure 6-6. Off-Leakage Current vs Source or Drain Voltage

100 125

6.11 Typical Characteristics (continued)

at T_A = 25°C, V_{DD} = +110V, and V_{SS} = -110V (unless otherwise noted)





7 Parameter Measurement Information

7.1 On-Resistance

The On-Resistance of the TMUX9612 is the ohmic resistance across the source (Sx) and drain (Dx) pins of the device. The On-Resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote On-Resistance. Figure 7-1 shows the measurement setup used to measure R_{ON} . ΔR_{ON} represents the difference between the R_{ON} of any two channels, while R_{ON_FLAT} denotes the flatness that is defined as the difference between the maximum and minimum value of On-Resistance measured over the specified analog signal range.

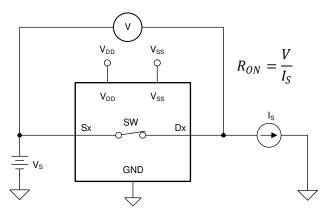


Figure 7-1. On-Resistance Measurement Setup

7.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

- Source Off-Leakage current I_{S(OFF)}: the leakage current flowing into or out of the source pin when the switch
 is off
- Drain Off-Leakage current I_{D(OFF)}: the leakage current flowing into or out of the drain pin when the switch is off.

Figure 7-2 shows the setup used to measure both Off-Leakage currents.

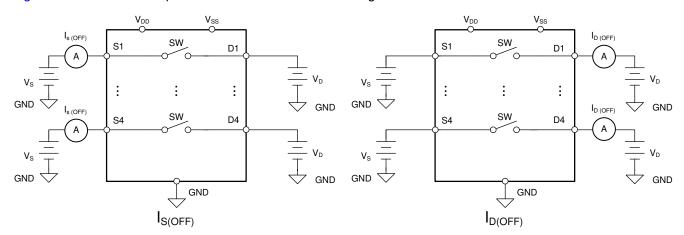


Figure 7-2. Off-Leakage Measurement Setup



7.3 On-Leakage Current

Source On-Leakage current $(I_{S(ON)})$ and drain On-Leakage current $(I_{D(ON)})$ denote the channel leakage currents when the switch is in the on state. $I_{S(ON)}$ is measured with the drain floating, while $I_{D(ON)}$ is measured with the source floating. Figure 7-3 shows the circuit used for measuring the On-Leakage currents.

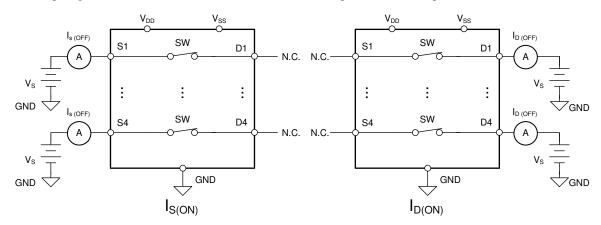


Figure 7-3. On-Leakage Measurement Setup

7.4 Device Turn-On and Turn-Off Time

Turn-On time (t_{ON}) is defined as the time taken by the output of the TMUX9612 to rise to a 90% final value after the SELx signal has risen (for NC switches) or fallen (for NO switches) to a 50% final value. Turn-Off time (t_{OFF}) is defined as the time taken by the output of the TMUX9612 to fall to a 10% initial value after the SELx signal has fallen (for NC switches) or risen (for NO switches) to a 50% initial value. Figure 7-4 shows the setup used to measure t_{ON} and t_{OFF} .

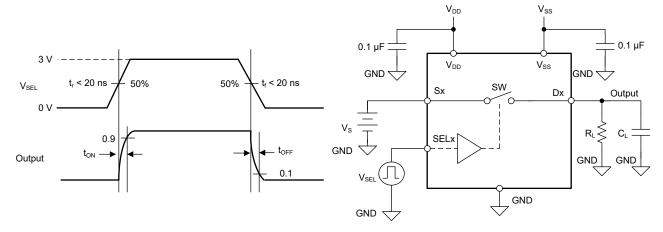


Figure 7-4. Enable Delay Measurement Setup



7.5 Charge Injection

Charge injection is a measure of the glitch impulse transferred from the digital input to the analog output during switching, and is denoted by the symbol Q_{INJ} . Figure 7-5 shows the setup used to measure charge injection from the source to drain.

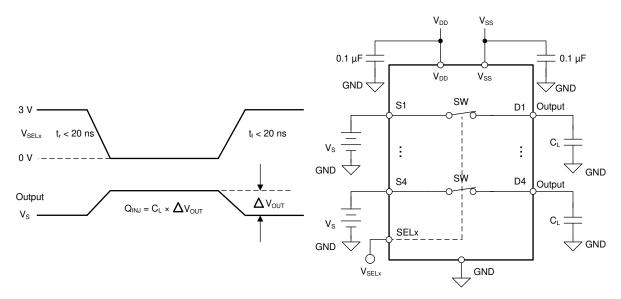


Figure 7-5. Charge-Injection Measurement Setup

7.6 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (Dx) of the device when a signal is applied to the source pin (Sx) of an off-channel. The characteristic impedance, Z_0 , for the measurement is 50Ω . Figure 7-6 and Equation 1 shows the setup used to measure off isolation.

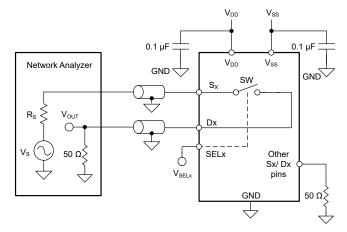


Figure 7-6. Off Isolation Measurement Setup

$$Off \, Isolation = 20 \times Log \, \frac{V_{OUT}}{V_S} \tag{1}$$



7.7 Crosstalk

Crosstalk (X_{TALK}) is defined as the ratio of the signal at the drain pin (Dx) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. The characteristic impedance, Z_0 , for the measurement is 50Ω , as shown in Figure 7-7 and Equation 2.

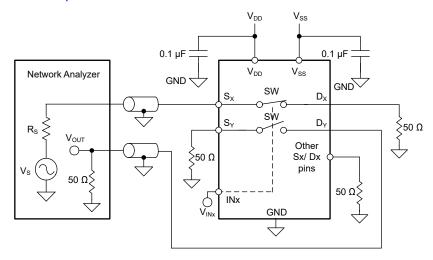


Figure 7-7. Inter-channel Crosstalk Measurement Setup

$$Inter-channel\ Crosstalk\ =\ 20\ \times\ Log\ \frac{V_{OUT}}{V_S} \tag{2}$$

7.8 Bandwidth

Bandwidth (BW) is defined as the range of frequencies that are attenuated by < 3dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (Dx). Figure 7-8 and Equation 3 shows the setup used to measure bandwidth of the switch.

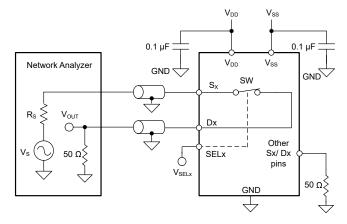


Figure 7-8. Bandwidth Measurement Setup

$$Bandwidth = 20 \times Log \frac{V_{OUT}}{V_S}$$
 (3)



7.9 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the multiplexer output. The On-Resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD+N. Figure 7-9 shows the setup used to measure THD+N of the devices.

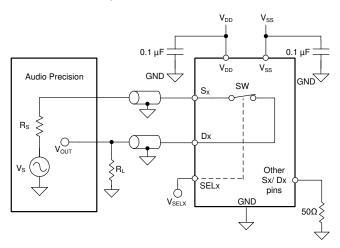


Figure 7-9. THD+N Measurement Setup

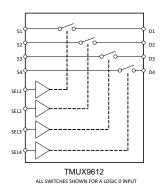


8 Detailed Description

8.1 Overview

The TMUX9612 is a modern complementary metal-oxide semiconductor (CMOS) analog switches in quad single-pole single-throw configuration. The device works well with dual supplies, a single supply, or asymmetric supplies.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Bidirectional Operation

The devices conduct equally well from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). Each signal path has similar characteristics in both directions.

8.3.2 Flat On-Resistance

The TMUX9612 devices are designed with a special switch architecture to produce ultra-flat On-Resistance (R_{ON}) across most of the switch input operating region. The flat R_{ON} response allows the device to be used in precision sensor applications since the R_{ON} is controlled regardless of the signals sampled. The architecture is implemented without a charge pump so no unwanted noise is produced from the device to affect sampling accuracy.

The flattest On-Resistance region extends from V_{SS} to roughly 5V below V_{DD}. Once the signal is within 5V of V_{DD} the On-Resistance will exponentially increase and may impact desired signal transmission.

8.3.3 Protection Features

These devices offer a number of protection features to enable robust system implementations.

8.3.3.1 Fail-Safe Logic

Fail-safe logic circuitry allows voltages on the logic control pins to be applied before the supply pins, protecting the device from potential damage. Additionally the fail safe logic feature allows the logic inputs of the mux to be interfaced with high voltages, allowing for simplified interfacing if only high voltage control signals are present. The logic inputs are protected against positive faults of up to +48V in powered-off condition, but do not offer protection against negative over-voltage condition.

Fail-safe logic also allows the devices to interface with a voltage greater than V_{DD} on the control pins during normal operation to add maximum flexibility in system design. For example, with a V_{DD} = 15V, the logic control pins could be connected to +24V for a logic high signal which allows different types of signals, such as analog feedback voltages, to be used when controlling the logic inputs. Regardless of the supply voltage, the logic inputs can be interfaced as high as 48V.

8.3.3.2 ESD Protection

All pins support HBM ESD protection level up to ±2kV, which helps protect the devices from ESD events during the manufacturing process.



8.3.3.3 Latch-Up Immunity

Latch-Up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or over-voltage), but once activated the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The Latch-Up condition typically requires a power cycle to eliminate the low impedance path.

In the TMUX9612 devices, an insulating oxide layer is placed on top of the silicon substrate to prevent any parasitic junctions from forming. As a result, the devices are Latch-Up immune under all circumstances by device construction.

The TMUX9612 devices are constructed on silicon on insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to over-voltage or current injections. The Latch-Up immunity feature allows the TMUX9612 to be used in harsh environments. For more information on Latch-Up immunity, refer to *Using Latch Up Immune Multiplexers to Help Improve System Reliability*.

8.3.4 1.8V Logic Compatible Inputs

The TMUX9612 devices have 1.8V logic compatible control for all logic control inputs. 1.8V logic level inputs allows the TMUX9612 to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and BOM cost. For more information on 1.8V logic implementations, refer to Simplifying Design with 1.8 V logic Muxes and Switches.

8.3.5 Integrated Pull-Down Resistor on Logic Pins

The TMUX9612 has internal weak Pull-Down resistors to GND to ensure the logic pins are not left floating. The value of this Pull-Down resistor is approximately $4M\Omega$, but is clamped to $1\mu A$ at higher voltages. This feature integrates up to four external components and reduces system size and cost.



8.4 Device Functional Modes

8.4.1 Normal Mode

In Normal Mode operation, signals of up to V_{DD} and V_{SS} can be passed through the switch from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). The select (SELx) pins determine which switch path to turn on, according to the Truth Table. The following conditions must be satisfied for the switch to stay in the ON condition:

- The difference between the primary supplies (V_{DD} V_{SS}) must be greater than or equal to 10V. With a minimum V_{DD} of 10V.
- The input signals on the source (Sx) or the drain (Dx) must be between V_{DD} and V_{SS}.
- The logic control (SELx) must have selected the switch.

8.4.2 Truth Tables

TMUX9612 Truth Table shows the truth tables for the TMUX9612.

Table 8-1. TMUX9612 Truth Table

SEL # ⁽¹⁾	CHANNEL #		
0	Channel # OFF		
1	Channel # ON		

(1) "#"designates the channel number controlled by SEL pin: "1, 2, 3, or 4"

If unused, then the SELx pins must be tied to GND or Logic High so that the devices do not consume additional current as highlighted in *Implications of Slow or Floating CMOS Inputs*. Unused signal path inputs (Sx or Dx) should be connected to GND for best performance.



9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The TMUX9612 is a high voltage switch capable of supporting analog and digital signals. The high voltage capability of these multiplexers allow them to be used in systems with high voltage signal swings, or in systems with high common mode voltages.

Additionally, the TMUX9612 provides consistent analog parametric performance across the entire supply voltage range allowing the devices to be powered by the most convenient supply rails in the system while still providing excellent performance.

9.2 Typical Application

A common feature of many PMUs (precision measurement units) is the ability to change current ranges. This allows for a system defined current clamp when testing devices and reduces possible damage to the PMU and DUT (device under test). In high voltage PMUs, large relays are often used to enable this switching, but this comes with the trade-off of size. To reduce system size, a multi-channel high voltage switch can be added to facilitate this switching with minimal impact to system size and performance. The TMUX9612 allows for switching between multiple current ranges, and has the added flexibility to use multiple channels in parallel for high current applications.

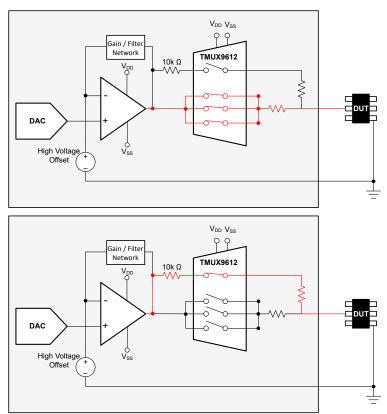


Figure 9-1. TMUX9612 Application Schematic

9.2.1 Design Requirements

Table 9-1. Design Parameters

PARAMETERS	VALUES			
Positive supply (V _{DD}) mux and Op Amps	110V			
Positive supply (V _{SS}) mux and Op Amps	-110V			
Maximum input or output signals with common mode shift	-110V to 110V			
Control logic thresholds	1.8V compatible, up to 48V			
Temperature range	-40°C to +125°C			

9.2.2 Detailed Design Procedure

Multiplexing PMU systems enables a small, flexible solution that can be used over a wide range of current ranges. This high voltage multiplexers offer a size advantage over typical relay solutions while still achieving an extremely low level of distortion, noise, and leakage. This high voltage multiplexer can be use in tandem with high voltage operational amplifiers and DACs to create an accurate PMU with excellent signal-to-noise ratio.

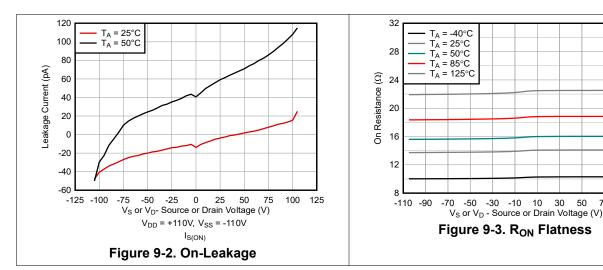
In this example application, the TMUX9612 is paired with a high voltage amplifier and a DAC. The DAC generates an arbitrary voltage signal that feeds into the amplifier. An additional high voltage offset is also fed into the amplifier to add any needed common mode shift. This arbitrary signal is then passed through a current limiting resistor before reaching the DUT. To change the current range of the system, different current limiting resistors are added in series with each channel of the multiplexer. In this example, the first channel of the multiplexer uses a $10k\Omega$ resistor for the low current clamp. The maximum output current of the PMU in this range is 5mA because of this design. During the system operation, the PMU is set to this lower current range in the beginning of the test routine. After the DUT is initially checked in this range and is operating normally with no unexpected shorts, the current range can be switched to high current. This way the PMU and DUT will not be unnecessarily damaged from excess current due to a short. In this example, the remaining three channels of the TMUX9612 are connected in parallel, increasing the maximum current through the device and reducing the low On-Resistance. Because of the flexibility of the TMUX9612, this could easily be modified to fit any system need. For example, if less maximum current is needed, then two channels could be connected in parallel instead of three, and the additional single channel could be used to add a third current range option. The additional input channels make this multiplexed application increasingly valuable by greatly reducing solution size.

The TMUX9612 switches have exceptionally flat On-Resistance and low leakage currents across the signal voltage range. The ultra-flat On-Resistance keeps the current clamp constant across the signal voltage range, and the low leakage current reduces the potential noise/offset when measuring on the lowest current range. Additionally, excellent crosstalk and off-isolation performance allows the TMUX9612 device to perform well in multi-channel switching applications without having an unselected channel impact the measurement on selected channels.



9.2.3 Application Curves

The example application utilizes the excellent leakage and On-Resistance flatness performance of the TMUX9612 device. Figure 9-2 shows the leakage current for a channel that is ON across a varying source voltage. Figure 9-3 shows the extremely flat On-Resistance across source voltage while operating within the flattest R_{ON} range of the TMUX9612 device. These features make the device an option for applications that require excellent linearity and low distortion.



9.3 Power Supply Recommendations

The TMUX9612 device operates across a wide supply range of ±10V to ±110V (10V to 140V in single-supply mode). It also performs well with asymmetrical supplies such as V_{DD} = 140V and V_{SS} = -80V or V_{DD} = 90V and V_{SS}= -130V. For improved supply noise immunity, use a supply decoupling capacitor ranging from 1μF to 10μF at both the V_{DD} and V_{SS} pins to ground. An additional 0.1µF capacitor placed closest to the supply pins will provide the best supply decoupling solution. Always ensure the ground (GND) connection is established before supplies are ramped.

VOUT is an internally generated voltage output rail. For reliable operation, connect a decoupling capacitor ranging from 0.01µF to 0.1µF between VOUT and GND on pin 10 or on the thermal pad. Having the decoupling capacitor as close to the thermal pad as possible yeilds the best performance.

9.4 Layout

9.4.1 Layout Guidelines

The image below illustrates an example of a PCB layout with the TMUX9612 device. Some key considerations are:

- For reliable operation, connect at least one decoupling capacitor ranging from 0.1µF to 10µF between V_{DD} and V_{SS} to GND. We recommend a $0.1\mu F$ and $1\mu F$ capacitor, placing the lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- For reliable operation, connect at least one decoupling capacitor ranging from 0.01µF to 0.1µF between VOUT to GND. We recommend a capacitor with sufficient voltage rating, that can keep its capacitance value to at least 0.01µF at 100V.
- Keep the input lines as short as possible.
- Use a solid ground plane to help distribute heat and reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.

30



9.4.2 Layout Example

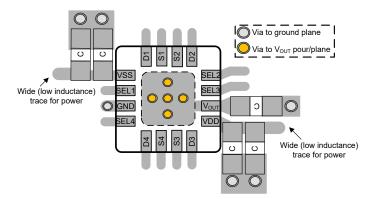


Figure 9-4. TMUX9612 Layout Example



10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Implications of Slow or Floating CMOS Inputs application note
- Texas Instruments, Multiplexers and Signal Switches Glossary application report
- Texas Instruments, Using Latch-Up Immune Multiplexers to Help Improve System Reliability application report

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Revision History

DATE	REVISION	NOTES				
July 2025	*	Initial APL Release				

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 7-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
PTMUX9612RUMR	Active	Preproduction	WQFN (RUM) 16	3000 LARGE T&R	-	Call TI	Call TI	-	

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

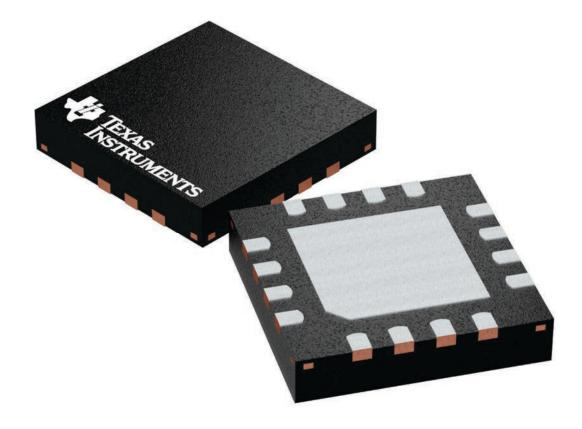
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

4 x 4, 0.65 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale, TI's General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025